



ESD



TVS



MOS



LDO



Diode



Sensor



DC-DC

Product Specification

▶ Domestic Part Number	IRF9389
▶ Overseas Part Number	IRF9389
▶ Equivalent Part Number	IRF9389



N+P-Channel MOSFET

Applications

- High and Low Side Switches for Inverter
- High and Low Side Switches for Generic Half-Bridge

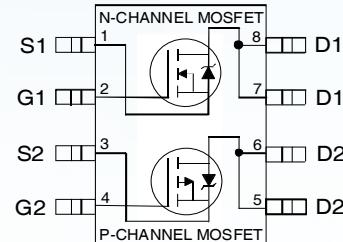
Features

N-Channel

- V_{DS} (V) = 30V
- I_D = 6.8A (V_{GS} = 10V)
- $R_{DS(ON)}$ < 27mΩ (V_{GS} = 10V)

P-Channel

- V_{DS} (V) = -30V
- I_D = -4.6A (V_{GS} = -10V)
- $R_{DS(ON)}$ < 64mΩ (V_{GS} = -10V)



Top View

Absolute Maximum Ratings

	Parameter	Max.		Units
		N-Channel	P-Channel	
V_{GS}	Gate-to-Source Voltage	± 20	± 20	V
I_D @ $T_A = 25^\circ\text{C}$	Continuous Drain Current, V_{GS} @ 10V	6.8	-4.6	A
I_D @ $T_A = 70^\circ\text{C}$	Continuous Drain Current, V_{GS} @ 10V	5.4	-3.7	
I_{DM}	Pulsed Drain Current ①	34	-23	
P_D @ $T_A = 25^\circ\text{C}$	Power Dissipation	2.0		W
P_D @ $T_A = 70^\circ\text{C}$	Power Dissipation	1.3		
	Linear Derating Factor	0.016		W/°C
T_J	Operating Junction and Storage Temperature Range	-55 to + 150		°C
T_{STG}				

Thermal Resistance

	Parameter	Typ.	Max	Units
$R_{\theta JL}$	Junction-to-Drain Lead ④	20	20	°C/W
$R_{\theta JA}$	Junction-to-Ambient ③		62.5	

N+P-Channel MOSFET**Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)**

	Parameter		Min.	Typ.	Max.	Units	
BV_{DSS}	Drain-to-Source Breakdown Voltage	N-Ch	30			V	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$
		P-Ch	-30				$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$
$\Delta \text{BV}_{\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	N-Ch		0.03		V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
		P-Ch		0.02			Reference to $25^\circ\text{C}, I_D = -1\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	N-Ch		22	27	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}, I_D = 6.8\text{A}$ ②
				33	40		$V_{\text{GS}} = 4.5\text{V}, I_D = 5.4\text{A}$ ②
		P-Ch		51	64	$\text{m}\Omega$	$V_{\text{GS}} = -10\text{V}, I_D = -4.6\text{A}$ ②
				82	103		$V_{\text{GS}} = -4.5\text{V}, I_D = -3.7\text{A}$ ②
$V_{\text{GS(th)}}$	Gate Threshold Voltage	N-Ch	1.3	1.8	2.3	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 10\mu\text{A}$
		P-Ch	-1.3	-1.8	-2.3		$V_{\text{DS}} = V_{\text{GS}}, I_D = -10\mu\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	N-Ch			1.0	μA	$V_{\text{DS}} = 24\text{V}, V_{\text{GS}} = 0\text{V}$
		P-Ch			-1.0		$V_{\text{DS}} = -24\text{V}, V_{\text{GS}} = 0\text{V}$
		N-Ch			150		$V_{\text{DS}} = 24\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
		P-Ch			-150		$V_{\text{DS}} = -24\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	N-Ch			100	nA	$V_{\text{GS}} = 20\text{V}$
		P-Ch			-100		$V_{\text{GS}} = -20\text{V}$
	Gate-to-Source Reverse Leakage	N-Ch			-100		$V_{\text{GS}} = -20\text{V}$
		P-Ch			100		$V_{\text{GS}} = 20\text{V}$
g_{fs}	Forward Transconductance	N-Ch	8.2			S	$V_{\text{DS}} = 15\text{V}, I_D = 5.4\text{A}$
		P-Ch	4.1				$V_{\text{DS}} = -15\text{V}, I_D = -3.7\text{A}$
Q_g	Total Gate Charge	N-Ch		6.8	14	nC	N-Channel
		P-Ch		8.1	16		$V_{\text{GS}} = 10\text{V}, V_{\text{DS}} = 15\text{V}, I_D = 6.8\text{A}$
Q_{gs}	Gate-to-Source Charge	N-Ch		1.4			P-Channel
		P-Ch		1.3			$V_{\text{GS}} = -10\text{V}, V_{\text{DS}} = -15\text{V}, I_D = -4.6\text{A}$
R_G	Gate Resistance	N-Ch		2.2	4.4	Ω	
		P-Ch		9.4	19		
$t_{\text{d(on)}}$	Turn-On Delay Time	N-Ch		5.1		ns	N-Channel
		P-Ch		8.0			$V_{\text{DD}} = 15\text{V}, V_{\text{GS}} = 4.5\text{V}$ ②
t_r	Rise Time	N-Ch		4.8			$I_D = 1.0\text{A}, R_G = 6.2$
		P-Ch		14			
$t_{\text{d(off)}}$	Turn-Off Delay Time	N-Ch		4.9			P-Channel
		P-Ch		17			$V_{\text{DD}} = -15\text{V}, V_{\text{GS}} = -4.5\text{V}$ ②
t_f	Fall Time	N-Ch		3.9			$I_D = -1.0\text{A}, R_G = 6.8$
		P-Ch		15			
C_{iss}	Input Capacitance	N-Ch		398		pF	N-Channel
		P-Ch		383			$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 15\text{V}, f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	N-Ch		82			P-Channel
		P-Ch		104			$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -15\text{V}, f = 1.0\text{KHz}$
C_{rss}	Reverse Transfer Capacitance	N-Ch		36			
		P-Ch		64			

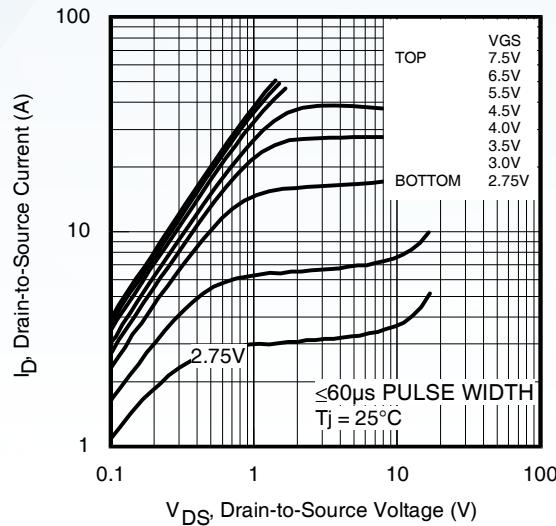
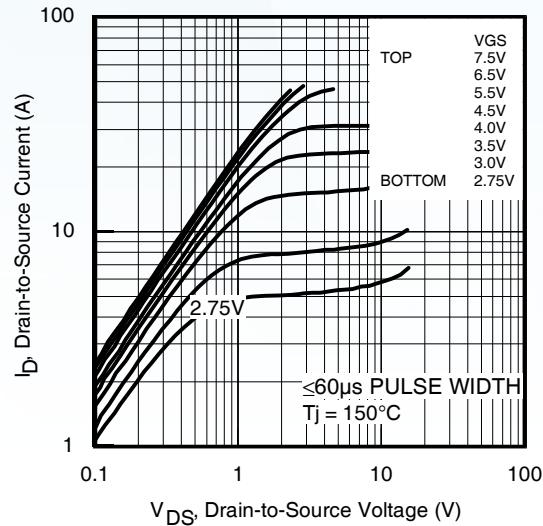
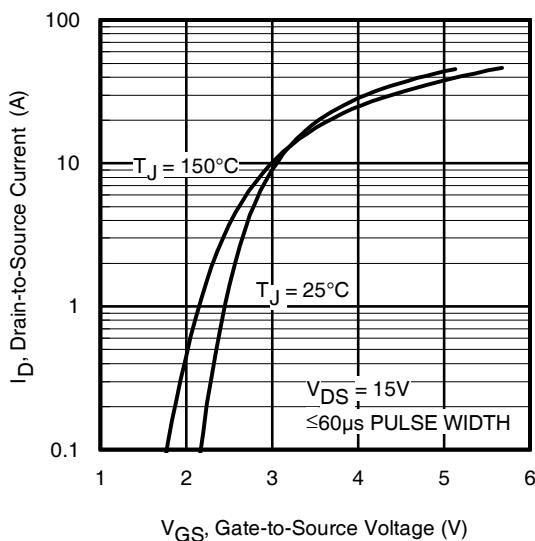
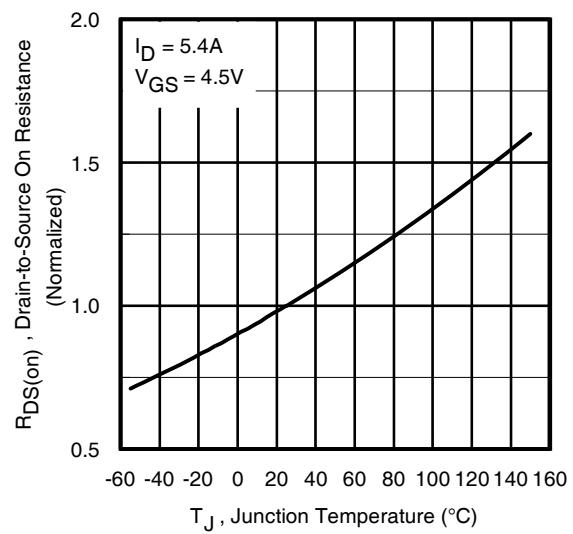
Diode Characteristics

	Parameter		Min.	Typ.	Max.	Units	Conditions
I_s	Continuous Source Current (Body Diode)	N-Ch			2.0	A	
		P-Ch			-2.0		
I_{SM}	Pulsed Source Current (Body Diode)	N-Ch			34		
		P-Ch			-23		
V_{SD}	Diode Forward Voltage	N-Ch			1.2	V	$T = 25^\circ\text{C}, I = 2.0\text{A}, V = 0\text{V}$ ②
		P-Ch			-1.2		$T = 25^\circ\text{C}, I = -2.0\text{A}, V = 0\text{V}$ ②
t_{rr}	Reverse Recovery Time	N-Ch		8.4	13	ns	N-Channel: $T = 25^\circ\text{C}, I = 2.0\text{A}, V_{\text{DD}} = 15\text{V}, di/dt = 102/\mu\text{s}$ ②
		P-Ch		11	17		P-Channel: $T = 25^\circ\text{C}, I = -2.0\text{A}, V_{\text{DD}} = -15\text{V}, di/dt = 102/\mu\text{s}$ ②
Q_{rr}	Reverse Recovery Charge	N-Ch		2.3	3.5	nC	
		P-Ch		4.8	7.2		

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 16)
 ② Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.

③ Surface mounted on 1 in square Cu board
 ④ R_θ is measured at T_J approximately 90°C

N+P-Channel MOSFET**Fig 1.** Typical Output Characteristics**Fig 2.** Typical Output Characteristics**Fig 3.** Typical Transfer Characteristics**Fig 4.** Normalized On-Resistance vs. Temperature

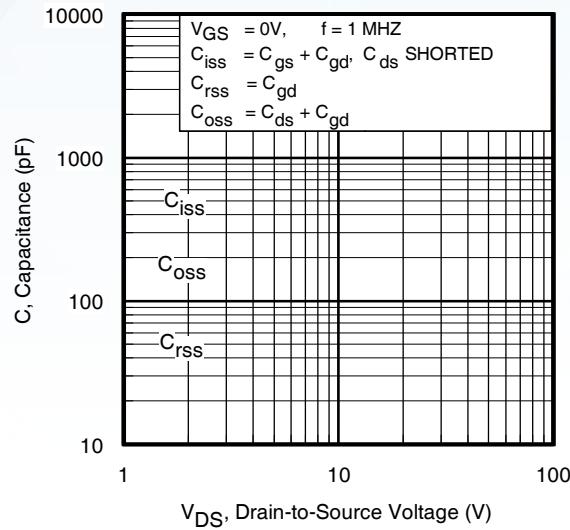
N+P-Channel MOSFET


Fig 5. Typical Capacitance vs.
Drain-to-Source Voltage

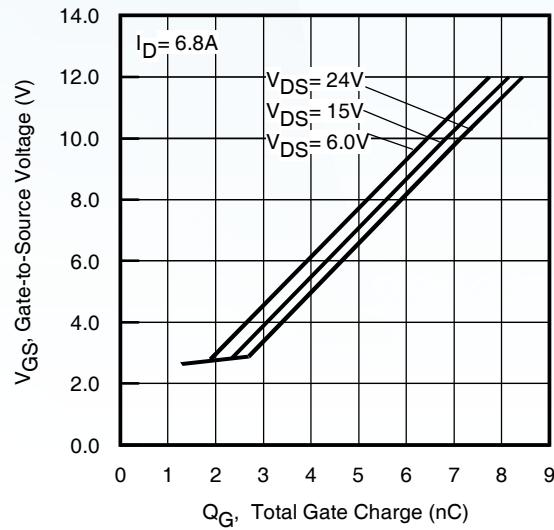


Fig 6. Typical Gate Charge vs.
Gate-to-Source Voltage

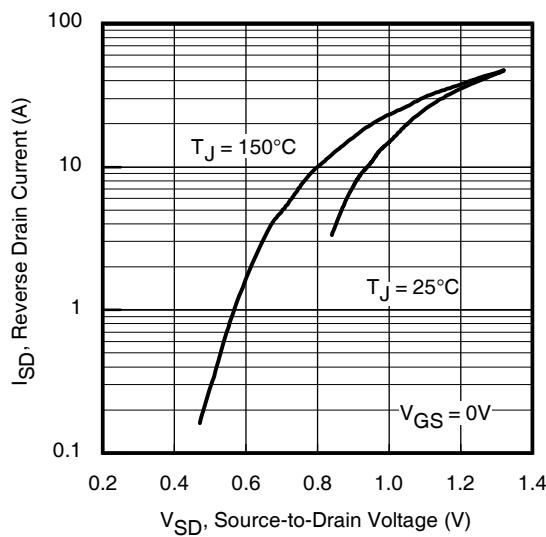


Fig 7. Typical Source-Drain Diode
Forward Voltage

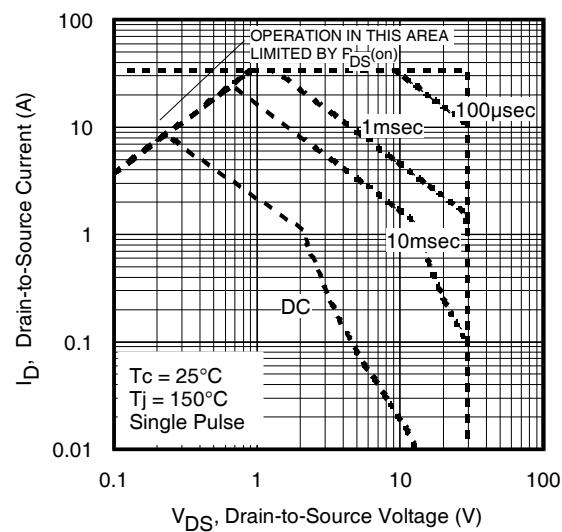


Fig 8. Maximum Safe Operating Area

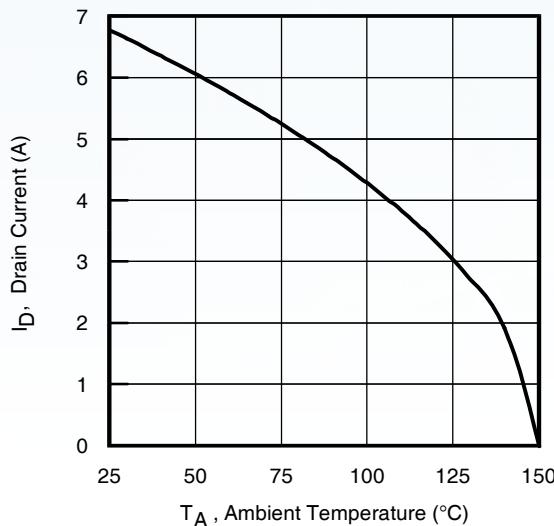


Fig 9. Maximum Drain Current vs. Ambient Temperature

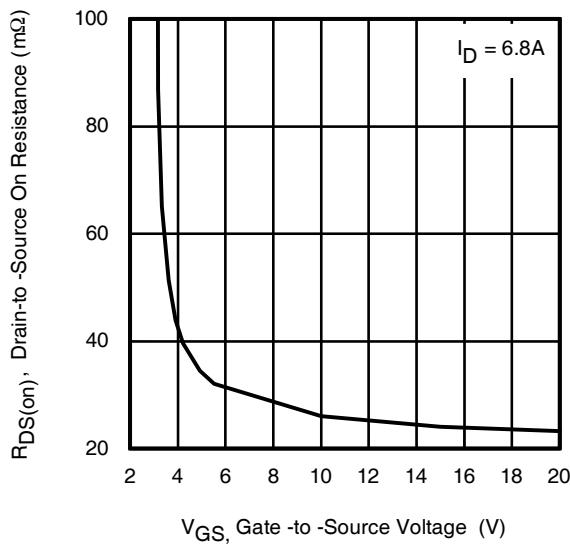


Fig 11. Typical On-Resistance vs. Gate Voltage

N+P-Channel MOSFET

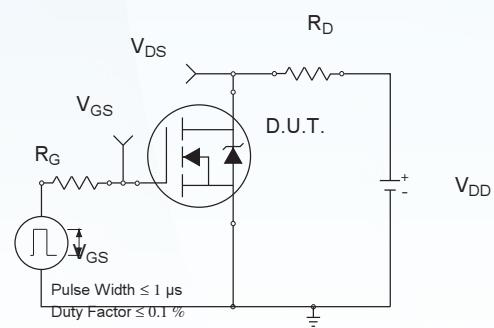


Fig 10a. Switching Time Test Circuit

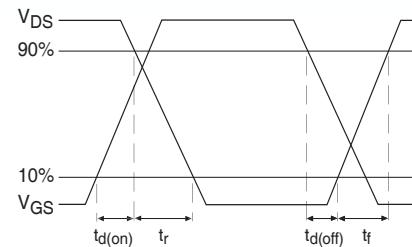


Fig 10b. Switching Time Waveforms

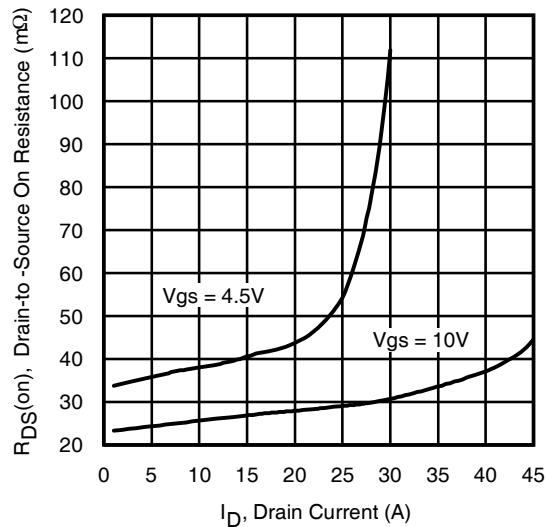
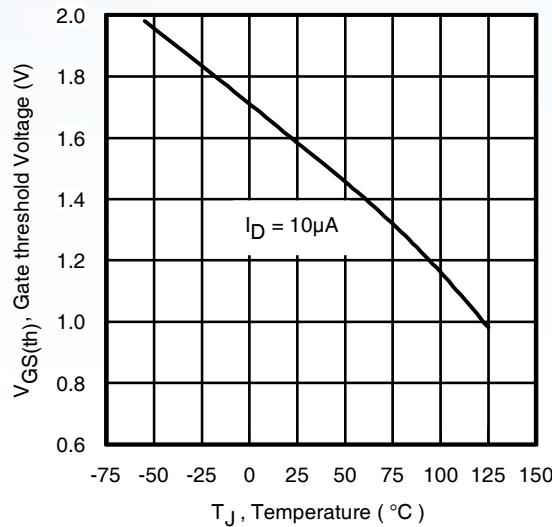
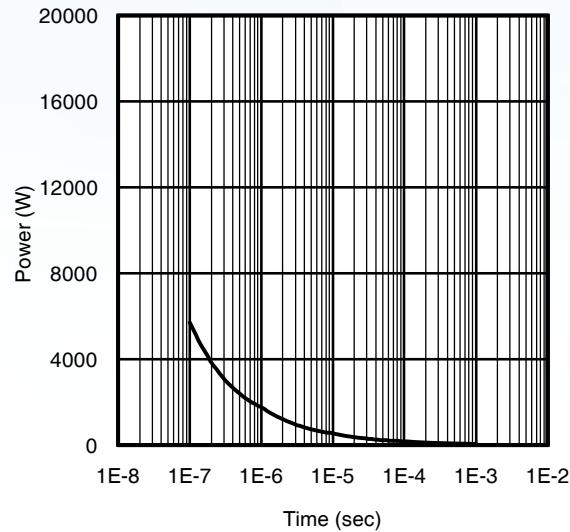
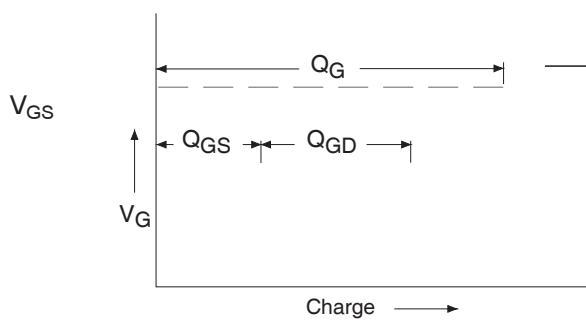
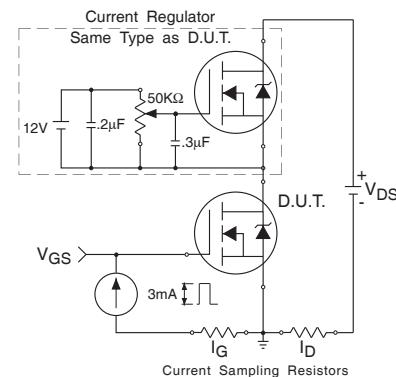
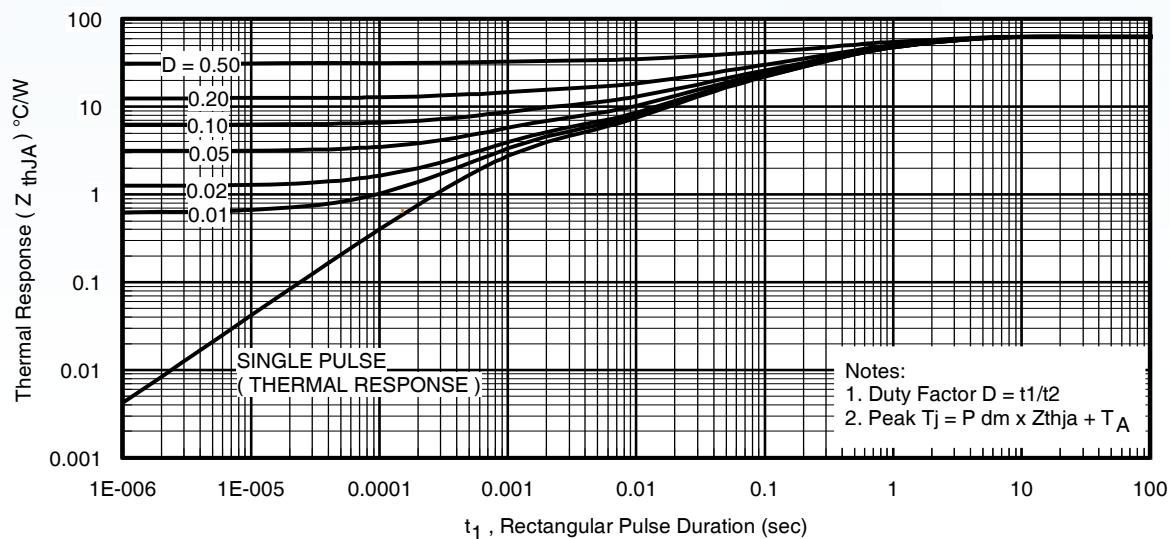
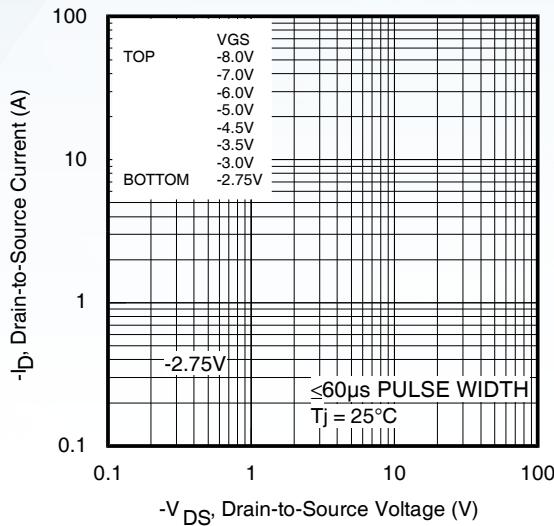
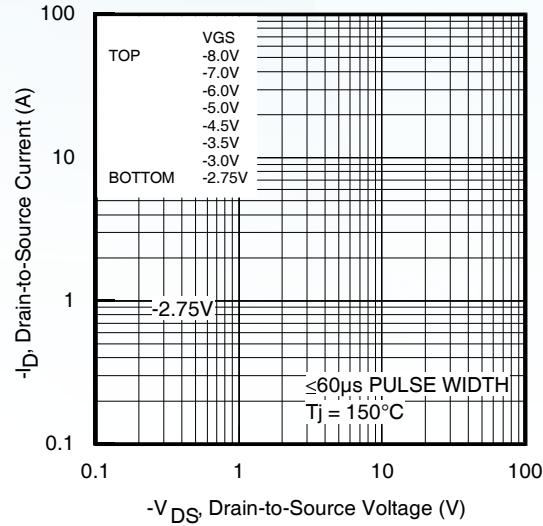
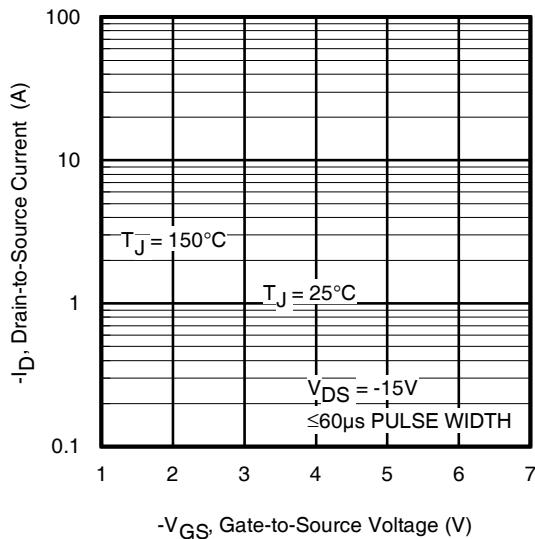
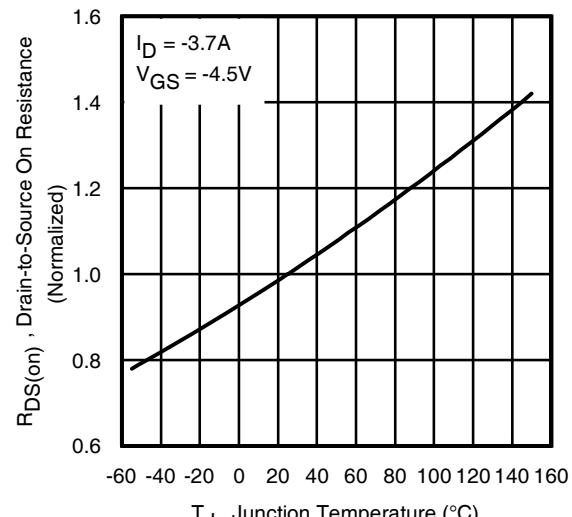


Fig 12. Typical On-Resistance vs. Drain Current

N+P-Channel MOSFET**Fig 13.** Threshold Voltage vs. Temperature**Fig 14.** Typical Power vs. Time**Fig 15a.** Basic Gate Charge Waveform**Fig 15b.** Gate Charge Test Circuit

N+P-Channel MOSFET**Fig 16.** Typical Effective Transient Thermal Impedance, Junction-to-Ambient

N+P-Channel MOSFET

Fig 17. Typical Output Characteristics

Fig 18. Typical Output Characteristics

Fig 19. Typical Transfer Characteristics

Fig 20. Normalized On-Resistance
vs. Temperature

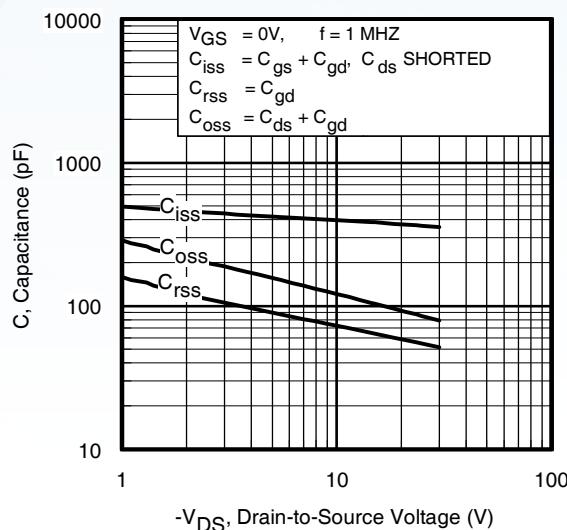
N+P-Channel MOSFET


Fig 21. Typical Capacitance vs.
Drain-to-Source Voltage

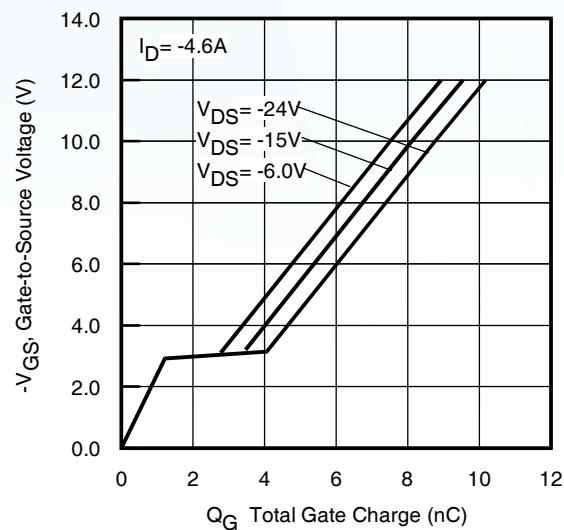


Fig 22. Typical Gate Charge vs.
Gate-to-Source Voltage

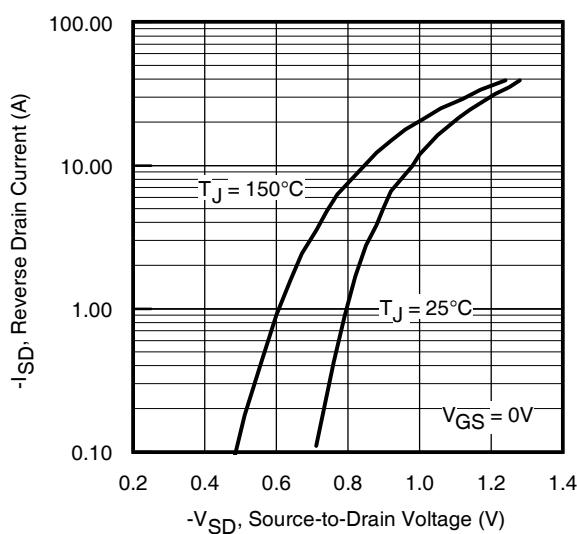


Fig 23. Typical Source-Drain Diode
Forward Voltage

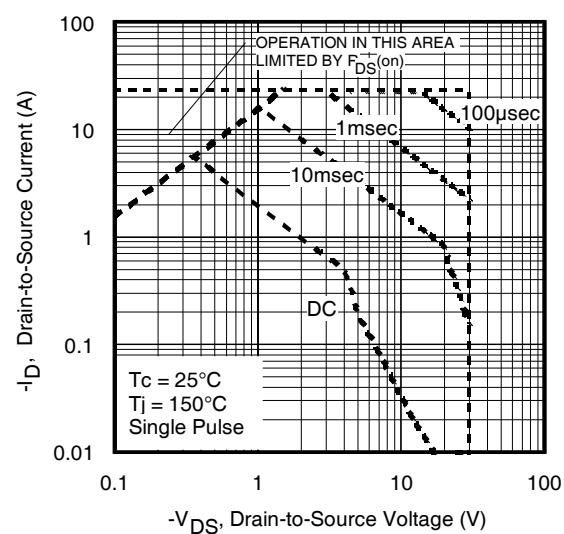


Fig 24. Maximum Safe Operating Area

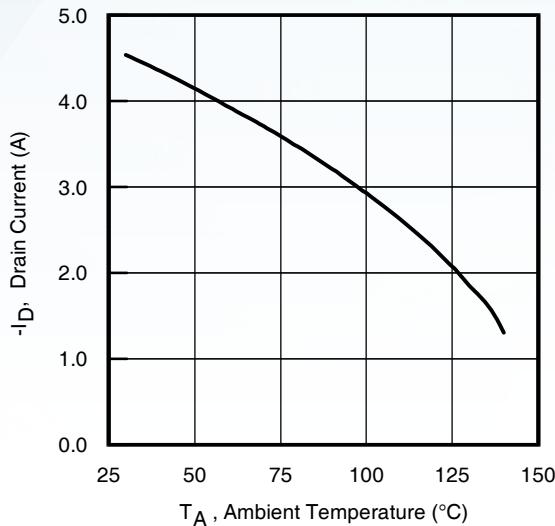


Fig 25. Maximum Drain Current vs. Ambient Temperature

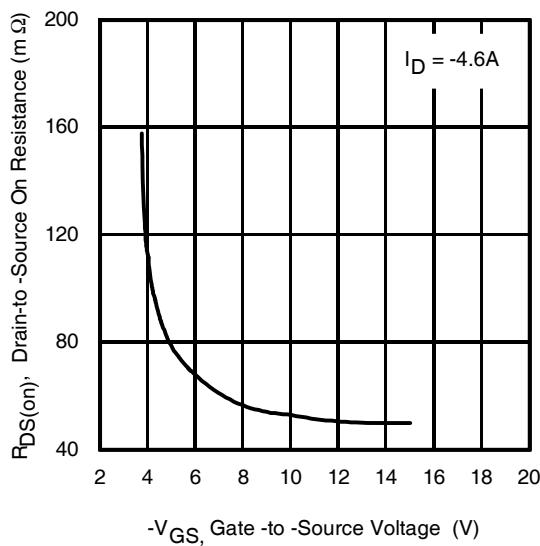


Fig 27. Typical On-Resistance vs. Gate Voltage

N+P-Channel MOSFET

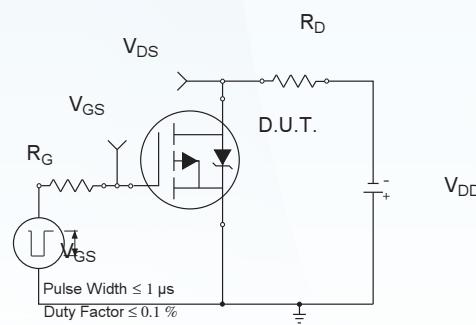


Fig 26a. Switching Time Test Circuit

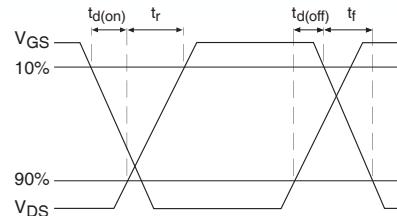


Fig 26b. Switching Time Waveforms

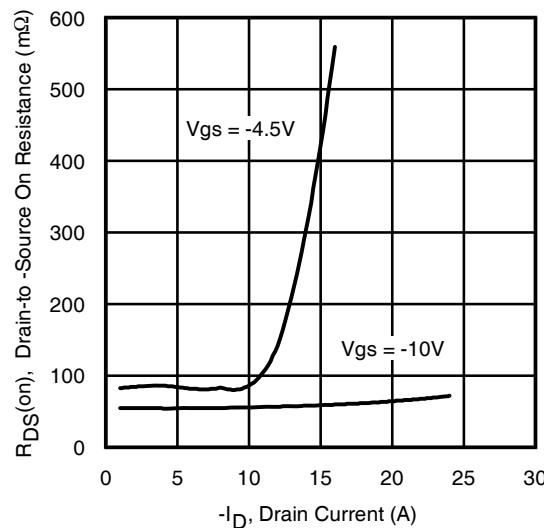
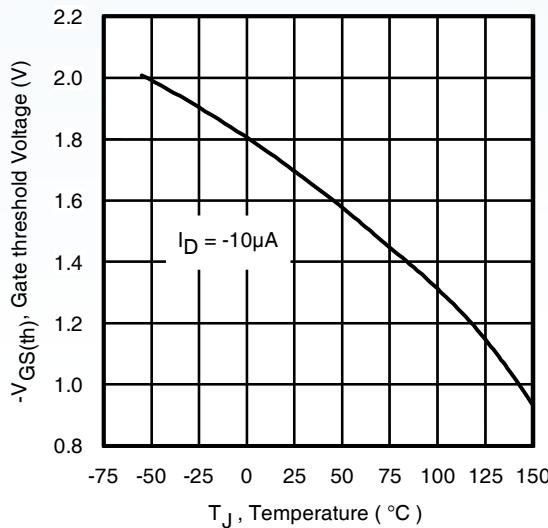
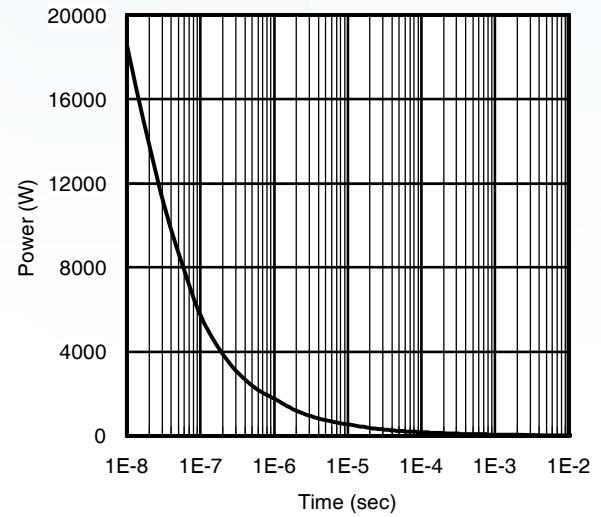
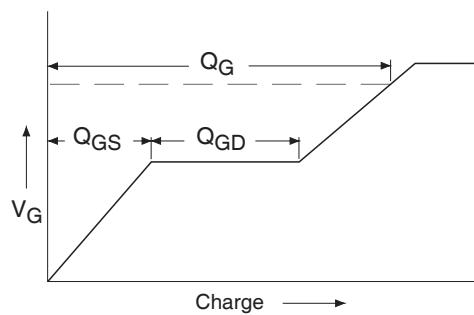
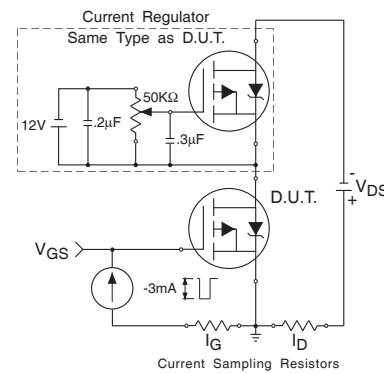
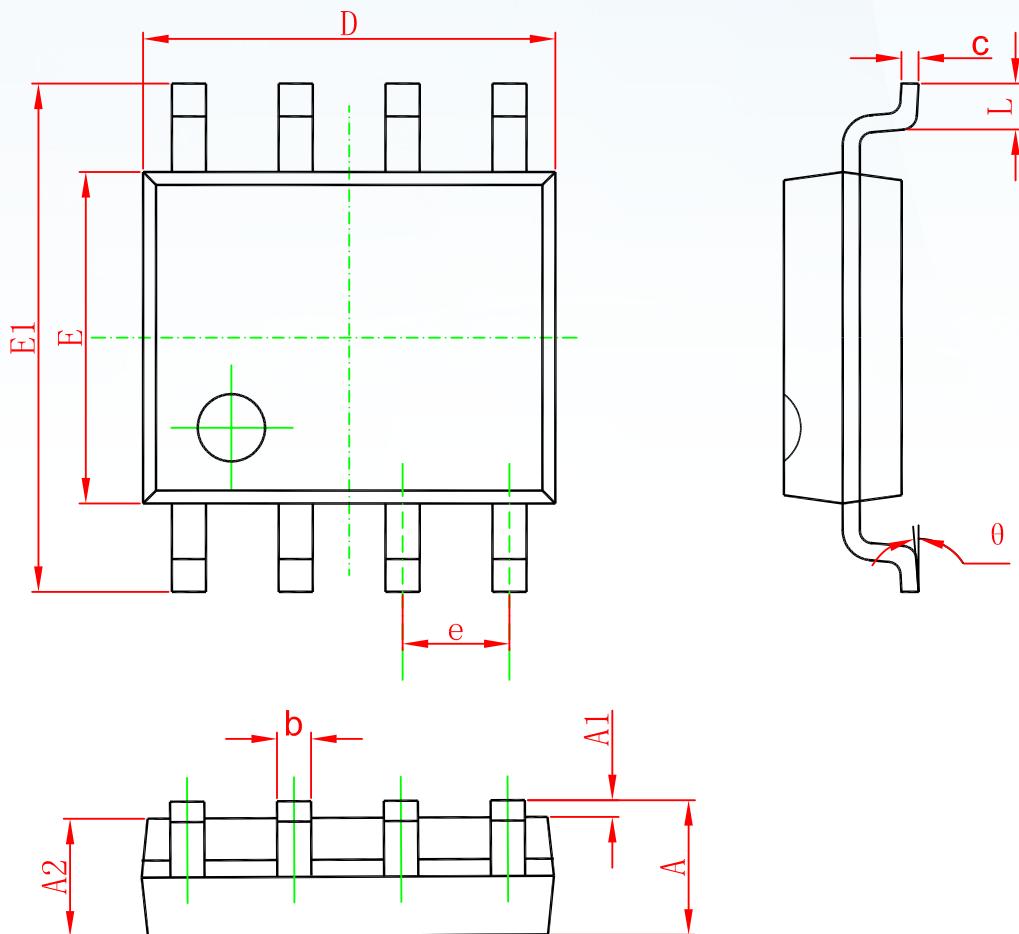


Fig 28. Typical On-Resistance vs. Drain Current

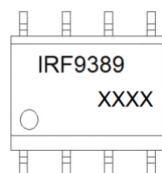
N+P-Channel MOSFET**Fig 29.** Threshold Voltage vs. Temperature**Fig 30.** Typical Power vs. Time**Fig 31a.** Basic Gate Charge Waveform**Fig 31b.** Gate Charge Test Circuit

Package Mechanical Data SOP-8

N+P-Channel MOSFET



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270(BSC)		0.050(BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°

N+P-Channel MOSFET**Marking****Ordering information**

Order code	Package	Baseqty	
IRF9389	SOP-8	3000	Tape and reel

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